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### Understanding Embedded - FPGAs (Field Programmable Gate Array)

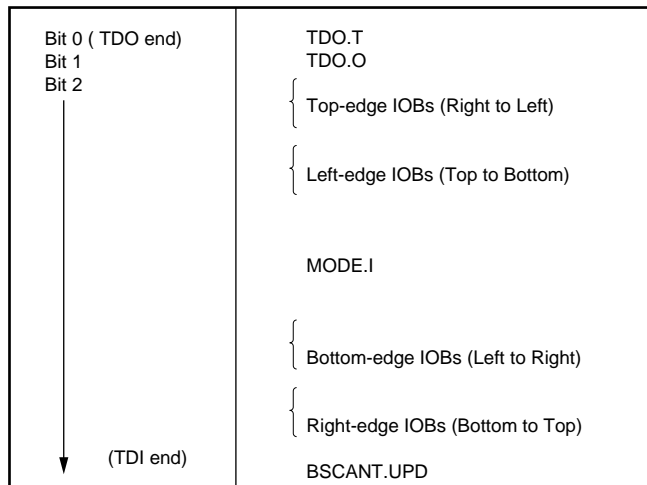
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	600
Number of Logic Elements/Cells	2700
Total RAM Bits	40960
Number of I/O	140
Number of Gates	100000
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xc2s100-5pqg208c">https://www.e-xfl.com/product-detail/xilinx/xc2s100-5pqg208c</a>



DS001\_10\_032300

Figure 10: Boundary Scan Bit Sequence

## Development System

Spartan-II FPGAs are supported by the Xilinx ISE® development tools. The basic methodology for Spartan-II FPGA design consists of three interrelated steps: design entry, implementation, and verification. Industry-standard tools are used for design entry and simulation, while Xilinx provides proprietary architecture-specific tools for implementation.

The Xilinx development system is integrated under a single graphical interface, providing designers with a common user interface regardless of their choice of entry and verification tools. The software simplifies the selection of implementation options with pull-down menus and on-line help.

For HDL design entry, the Xilinx FPGA development system provides interfaces to several synthesis design environments.

A standard interface-file specification, Electronic Design Interchange Format (EDIF), simplifies file transfers into and out of the development system.

Spartan-II FPGAs supported by a unified library of standard functions. This library contains over 400 primitives and macros, ranging from 2-input AND gates to 16-bit accumulators, and includes arithmetic functions, comparators, counters, data registers, decoders, encoders, I/O functions, latches, Boolean functions, multiplexers, shift registers, and barrel shifters.

The design environment supports hierarchical design entry. These hierarchical design elements are automatically combined by the implementation tools. Different design entry tools can be combined within a hierarchical design, thus allowing the most convenient entry method to be used for each portion of the design.

## Design Implementation

The place-and-route tools (PAR) automatically provide the implementation flow described in this section. The partitioner takes the EDIF netlist for the design and maps the logic into the architectural resources of the FPGA (CLBs and IOBs, for example). The placer then determines the best locations for these blocks based on their interconnections and the desired performance. Finally, the router interconnects the blocks.

The PAR algorithms support fully automatic implementation of most designs. For demanding applications, however, the user can exercise various degrees of control over the process. User partitioning, placement, and routing information is optionally specified during the design-entry process. The implementation of highly structured designs can benefit greatly from basic floorplanning.

The implementation software incorporates timing-driven placement and routing. Designers specify timing requirements along entire paths during design entry. The timing path analysis routines in PAR then recognize these user-specified requirements and accommodate them.

Timing requirements are entered in a form directly relating to the system requirements, such as the targeted clock frequency, or the maximum allowable delay between two registers. In this way, the overall performance of the system along entire signal paths is automatically tailored to user-generated specifications. Specific timing information for individual nets is unnecessary.

## Design Verification

In addition to conventional software simulation, FPGA users can use in-circuit debugging techniques. Because Xilinx devices are infinitely reprogrammable, designs can be verified in real time without the need for extensive sets of software simulation vectors.

The development system supports both software simulation and in-circuit debugging techniques. For simulation, the system extracts the post-layout timing information from the design database, and back-annotates this information into the netlist for use by the simulator. Alternatively, the user can verify timing-critical portions of the design using the static timing analyzer.

For in-circuit debugging, the development system includes a download cable, which connects the FPGA in the target system to a PC or workstation. After downloading the design into the FPGA, the designer can read back the contents of the flip-flops, and so observe the internal logic state. Simple modifications can be downloaded into the system in a matter of minutes.

## BUFGDLL Pin Descriptions

Use the BUFGDLL macro as the simplest way to provide zero propagation delay for a high-fanout on-chip clock from an external input. This macro uses the IBUFG, CLKDLL and BUFG primitives to implement the most basic DLL application as shown in Figure 25.

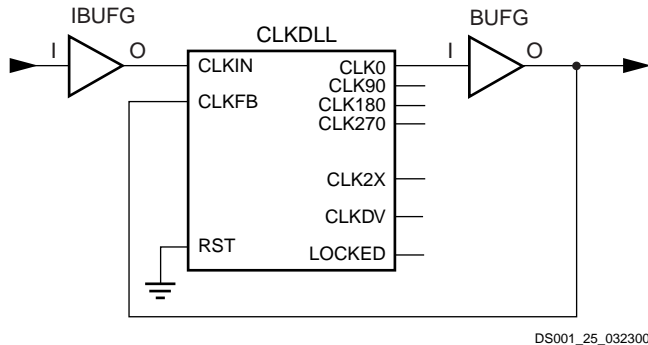


Figure 25: BUFGDLL Block Diagram

This macro does not provide access to the advanced clock domain controls or to the clock multiplication or clock division features of the DLL. This macro also does not provide access to the RST or LOCKED pins of the DLL. For access to these features, a designer must use the DLL primitives described in the following sections.

### Source Clock Input — I

The I pin provides the user source clock, the clock signal on which the DLL operates, to the BUFGDLL. For the BUFGDLL macro the source clock frequency must fall in the low frequency range as specified in the data sheet. The BUFGDLL requires an external signal source clock. Therefore, only an external input port can source the signal that drives the BUFGDLL I pin.

### Clock Output — O

The clock output pin O represents a delay-compensated version of the source clock (I) signal. This signal, sourced by a global clock buffer BUFG primitive, takes advantage of the dedicated global clock routing resources of the device.

The output clock has a 50/50 duty cycle unless you deactivate the duty cycle correction property.

## CLKDLL Primitive Pin Descriptions

The library CLKDLL primitives provide access to the complete set of DLL features needed when implementing more complex applications with the DLL.

### Source Clock Input — CLKIN

The CLKIN pin provides the user source clock (the clock signal on which the DLL operates) to the DLL. The CLKIN frequency must fall in the ranges specified in the data sheet. A global clock buffer (BUFG) driven from another CLKDLL

or one of the global clock input buffers (IBUFG) on the same edge of the device (top or bottom) must source this clock signal.

### Feedback Clock Input — CLKFB

The DLL requires a reference or feedback signal to provide the delay-compensated output. Connect only the CLK0 or CLK2X DLL outputs to the feedback clock input (CLKFB) pin to provide the necessary feedback to the DLL. Either a global clock buffer (BUFG) or one of the global clock input buffers (IBUFG) on the same edge of the device (top or bottom) must source this clock signal.

If an IBUFG sources the CLKFB pin, the following special rules apply.

1. An external input port must source the signal that drives the IBUFG I pin.
2. The CLK2X output must feed back to the device if both the CLK0 and CLK2X outputs are driving off chip devices.
3. That signal must directly drive only OBUFs and nothing else.

These rules enable the software to determine which DLL clock output sources the CLKFB pin.

### Reset Input — RST

When the reset pin RST activates, the LOCKED signal deactivates within four source clock cycles. The RST pin, active High, must either connect to a dynamic signal or be tied to ground. As the DLL delay taps reset to zero, glitches can occur on the DLL clock output pins. Activation of the RST pin can also severely affect the duty cycle of the clock output pins. Furthermore, the DLL output clocks no longer deskew with respect to one another. The DLL must be reset when the input clock frequency changes, if the device is reconfigured in Boundary-Scan mode, if the device undergoes a hot swap, and after the device is configured if the input clock is not stable during the startup sequence.

### 2x Clock Output — CLK2X

The output pin CLK2X provides a frequency-doubled clock with an automatic 50/50 duty-cycle correction. Until the CLKDLL has achieved lock, the CLK2X output appears as a 1x version of the input clock with a 25/75 duty cycle. This behavior allows the DLL to lock on the correct edge with respect to source clock. This pin is not available on the CLKDLLHF primitive.

### Clock Divide Output — CLKDV

The clock divide output pin CLKDV provides a lower frequency version of the source clock. The CLKDV\_DIVIDE property controls CLKDV such that the source clock is divided by N where N is either 1.5, 2, 2.5, 3, 4, 5, 8, or 16.

This feature provides automatic duty cycle correction. The CLKDV output pin has a 50/50 duty cycle for all values of the

division factor N except for non-integer division in High Frequency (HF) mode. For division factor 1.5 the duty cycle in the HF mode is 33.3% High and 66.7% Low. For division factor 2.5, the duty cycle in the HF mode is 40.0% High and 60.0% Low.

### 1x Clock Outputs — CLK[0/90/180/270]

The 1x clock output pin CLK0 represents a delay-compensated version of the source clock (CLKIN) signal. The CLKDLL primitive provides three phase-shifted versions of the CLK0 signal while CLKDLLHF provides only the 180 degree phase-shifted version. The relationship between phase shift and the corresponding period shift appears in [Table 10](#).

The timing diagrams in [Figure 26](#) illustrate the DLL clock output characteristics.

**Table 10: Relationship of Phase-Shifted Output Clock to Period Shift**

Phase (degrees)	Period Shift (percent)
0	0%
90	25%
180	50%
270	75%

The DLL provides duty cycle correction on all 1x clock outputs such that all 1x clock outputs by default have a 50/50 duty cycle. The DUTY\_CYCLE\_CORRECTION property (TRUE by default), controls this feature. In order to deactivate the DLL duty cycle correction, attach the DUTY\_CYCLE\_CORRECTION=FALSE property to the DLL primitive. When duty cycle correction deactivates, the output clock has the same duty cycle as the source clock.

The DLL clock outputs can drive an OBUF, a BUFG, or they can route directly to destination clock pins. The DLL clock outputs can only drive the BUFGs that reside on the same edge (top or bottom).

### Locked Output — LOCKED

In order to achieve lock, the DLL may need to sample several thousand clock cycles. After the DLL achieves lock the LOCKED signal activates. The ["DLL Timing Parameters"](#) section of Module 3 provides estimates for locking times.

In order to guarantee that the system clock is established prior to the device "waking up," the DLL can delay the completion of the device configuration process until after the DLL locks. The STARTUP\_WAIT property activates this feature.

Until the LOCKED signal activates, the DLL output clocks are not valid and can exhibit glitches, spikes, or other

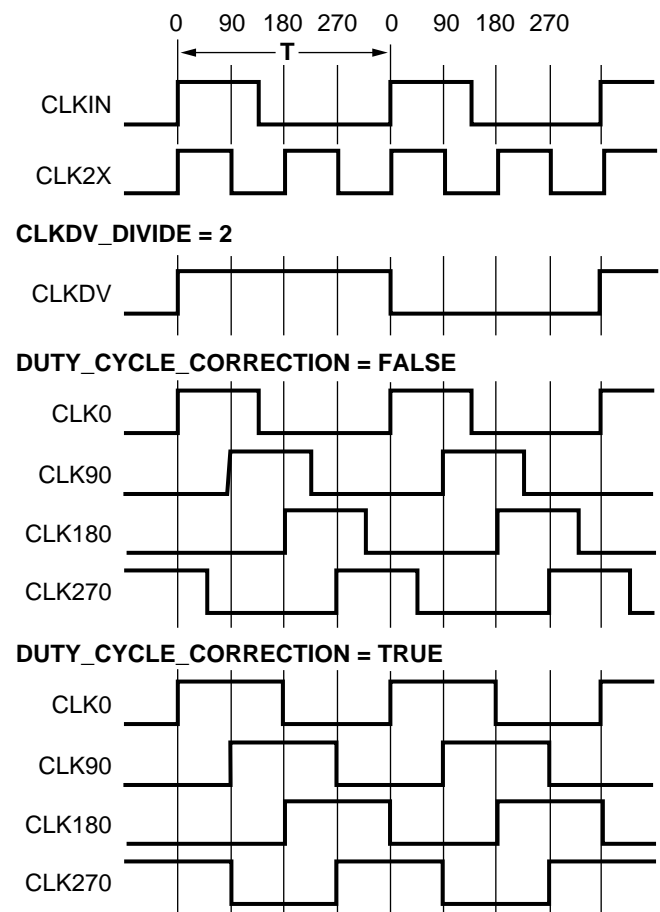
spurious movement. In particular the CLK2X output will appear as a 1x clock with a 25/75 duty cycle.

### DLL Properties

Properties provide access to some of the Spartan-II family DLL features, (for example, clock division and duty cycle correction).

### Duty Cycle Correction Property

The 1x clock outputs, CLK0, CLK90, CLK180, and CLK270, use the duty-cycle corrected default, such that they exhibit a 50/50 duty cycle. The DUTY\_CYCLE\_CORRECTION property (by default TRUE) controls this feature. To deactivate the DLL duty-cycle correction for the 1x clock outputs, attach the DUTY\_CYCLE\_CORRECTION=FALSE property to the DLL primitive.



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**Figure 26: DLL Output Characteristics**

### Clock Divide Property

The CLKDV\_DIVIDE property specifies how the signal on the CLKDV pin is frequency divided with respect to the CLK0 pin. The values allowed for this property are 1.5, 2, 2.5, 3, 4, 5, 8, or 16; the default value is 2.

## Startup Delay Property

This property, `STARTUP_WAIT`, takes on a value of `TRUE` or `FALSE` (the default value). When `TRUE` the Startup Sequence following device configuration is paused at a user-specified point until the DLL locks. [XAPP176: Configuration and Readback of the Spartan-II and Spartan-IIe Families](#) explains how this can result in delaying the assertion of the `DONE` pin until the DLL locks.

## DLL Location Constraints

The DLLs are distributed such that there is one DLL in each corner of the device. The location constraint `LOC`, attached to the DLL primitive with the numeric identifier 0, 1, 2, or 3, controls DLL location. The orientation of the four DLLs and their corresponding clock resources appears in [Figure 27](#).

The `LOC` property uses the following form.

`LOC = DLL2`

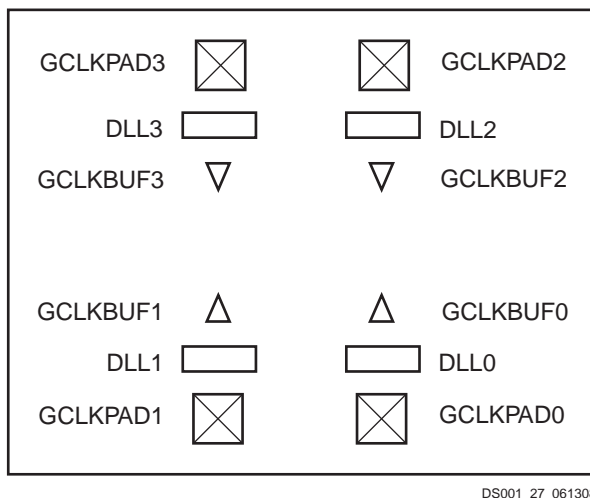


Figure 27: Orientation of DLLs

## Design Considerations

Use the following design considerations to avoid pitfalls and improve success designing with Xilinx devices.

### Input Clock

The output clock signal of a DLL, essentially a delayed version of the input clock signal, reflects any instability on the input clock in the output waveform. For this reason the quality of the DLL input clock relates directly to the quality of the output clock waveforms generated by the DLL. The DLL input clock requirements are specified in the ["DLL Timing Parameters"](#) section of the data sheet.

In most systems a crystal oscillator generates the system clock. The DLL can be used with any commercially available quartz crystal oscillator. For example, most crystal oscillators produce an output waveform with a frequency tolerance of 100 PPM, meaning 0.01 percent change in the

clock period. The DLL operates reliably on an input waveform with a frequency drift of up to 1 ns — orders of magnitude in excess of that needed to support any crystal oscillator in the industry. However, the cycle-to-cycle jitter must be kept to less than 300 ps in the low frequencies and 150 ps for the high frequencies.

### Input Clock Changes

Changing the period of the input clock beyond the maximum drift amount requires a manual reset of the `CLKDLL`. Failure to reset the DLL will produce an unreliable lock signal and output clock.

It is possible to stop the input clock in a way that has little impact to the DLL. Stopping the clock should be limited to less than approximately 100  $\mu$ s to keep device cooling to a minimum and maintain the validity of the current tap setting. The clock should be stopped during a Low phase, and when restored the full High period should be seen. During this time `LOCKED` will stay High and remain High when the clock is restored. If these conditions may not be met in the design, apply a manual reset to the DLL after re-starting the input clock, even if the `LOCKED` signal has not changed.

When the clock is stopped, one to four more clocks will still be observed as the delay line is flushed. When the clock is restarted, the output clocks will not be observed for one to four clocks as the delay line is filled. The most common case will be two or three clocks.

In a similar manner, a phase shift of the input clock is also possible. The phase shift will propagate to the output one to four clocks after the original shift, with no disruption to the `CLKDLL` control.

### Output Clocks

As mentioned earlier in the DLL pin descriptions, some restrictions apply regarding the connectivity of the output pins. The DLL clock outputs can drive an `OBUF`, a global clock buffer `BUFG`, or route directly to destination clock pins. The only `BUFGs` that the DLL clock outputs can drive are the two on the same edge of the device (top or bottom). One DLL output can drive more than one `OBUF`; however, this adds skew.

Do not use the DLL output clock signals until after activation of the `LOCKED` signal. Prior to the activation of the `LOCKED` signal, the DLL output clocks are not valid and can exhibit glitches, spikes, or other spurious movement.



Table 11: Available Library Primitives

Primitive	Port A Width	Port B Width
RAMB4_S4	4	N/A
RAMB4_S4_S4		4
RAMB4_S4_S8		8
RAMB4_S4_S16		16
RAMB4_S8	8	N/A
RAMB4_S8_S8		8
RAMB4_S8_S16		16
RAMB4_S16	16	N/A
RAMB4_S16_S16		16

## Port Signals

Each block RAM port operates independently of the others while accessing the same set of 4096 memory cells.

Table 12 describes the depth and width aspect ratios for the block RAM memory.

Table 12: Block RAM Port Aspect Ratios

Width	Depth	ADDR Bus	Data Bus
1	4096	ADDR<11:0>	DATA<0>
2	2048	ADDR<10:0>	DATA<1:0>
4	1024	ADDR<9:0>	DATA<3:0>
8	512	ADDR<8:0>	DATA<7:0>
16	256	ADDR<7:0>	DATA<15:0>

## Clock—CLK[A/B]

Each port is fully synchronous with independent clock pins. All port input pins have setup time referenced to the port CLK pin. The data output bus has a clock-to-out time referenced to the CLK pin.

## Enable—EN[A/B]

The enable pin affects the read, write and reset functionality of the port. Ports with an inactive enable pin keep the output pins in the previous state and do not write data to the memory cells.

## Write Enable—WE[A/B]

Activating the write enable pin allows the port to write to the memory cells. When active, the contents of the data input bus are written to the RAM at the address pointed to by the address bus, and the new data also reflects on the data out bus. When inactive, a read operation occurs and the contents of the memory cells referenced by the address bus reflect on the data out bus.

## Reset—RST[A/B]

The reset pin forces the data output bus latches to zero synchronously. This does not affect the memory cells of the RAM and does not disturb a write operation on the other port.

## Address Bus—ADDR[A/B]<#:0>

The address bus selects the memory cells for read or write. The width of the port determines the required width of this bus as shown in Table 12.

## Data In Bus—DI[A/B]<#:0>

The data in bus provides the new data value to be written into the RAM. This bus and the port have the same width, as shown in Table 12.

## Data Output Bus—DO[A/B]<#:0>

The data out bus reflects the contents of the memory cells referenced by the address bus at the last active clock edge. During a write operation, the data out bus reflects the data in bus. The width of this bus equals the width of the port. The allowed widths appear in Table 12.

## Inverting Control Pins

The four control pins (CLK, EN, WE and RST) for each port have independent inversion control as a configuration option.

## Address Mapping

Each port accesses the same set of 4096 memory cells using an addressing scheme dependent on the width of the port. The physical RAM location addressed for a particular width are described in the following formula (of interest only when the two ports use different aspect ratios).

$$\text{Start} = ([\text{ADDR}_{\text{port}} + 1] * \text{Width}_{\text{port}}) - 1$$

$$\text{End} = \text{ADDR}_{\text{port}} * \text{Width}_{\text{port}}$$

Table 13 shows low order address mapping for each port width.

Table 13: Port Address Mapping

Port Width	Port Addresses																
1	4095...	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
2	2047...	07		06		05		04		03		02		01		00	
4	1023...	03				02				01				00			
8	511...	01								00							
16	255...	00															

LVTTL output buffers have selectable drive strengths.

The format for LVTTL OBUF primitive names is as follows.

OBUF\_<slew\_rate>\_<drive\_strength>

<slew\_rate> is either F (Fast), or S (Slow) and <drive\_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24). The default is slew rate limited with 12 mA drive.

OBUF placement restrictions require that within a given  $V_{CCO}$  bank each OBUF share the same output source drive voltage. Input buffers of any type and output buffers that do not require  $V_{CCO}$  can be placed within any  $V_{CCO}$  bank.

Table 17 summarizes the output compatibility requirements. The LOC property can specify a location for the OBUF.

Table 17: Output Standards Compatibility Requirements

Rule 1	Only outputs with standards which share compatible $V_{CCO}$ may be used within the same bank.
Rule 2	There are no placement restrictions for outputs with standards that do not require a $V_{CCO}$ .
$V_{CCO}$	Compatible Standards
3.3	LVTTL, SSTL3_I, SSTL3_II, CTT, AGP, GTL, GTL+, PCI33_3, PCI66_3
2.5	SSTL2_I, SSTL2_II, LVCMOS2, GTL, GTL+
1.5	HSTL_I, HSTL_III, HSTL_IV, GTL, GTL+

## OBUFT

The generic 3-state output buffer OBUFT, shown in Figure 39, typically implements 3-state outputs or bidirectional I/O.

With no extension or property specified for the generic OBUFT primitive, the assumed standard is slew rate limited LVTTL with 12 mA drive strength.

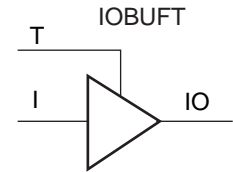
The LVTTL OBUFT can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL 3-state output buffers have selectable drive strengths.

The format for LVTTL OBUFT primitive names is as follows.

OBUFT\_<slew\_rate>\_<drive\_strength>

<slew\_rate> can be either F (Fast), or S (Slow) and <drive\_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24).



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Figure 39: 3-State Output Buffer Primitive (OBUFT)

The Versatile I/O OBUFT placement restrictions require that within a given  $V_{CCO}$  bank each OBUFT share the same output source drive voltage. Input buffers of any type and output buffers that do not require  $V_{CCO}$  can be placed within the same  $V_{CCO}$  bank.

The LOC property can specify a location for the OBUFT.

3-state output buffers and bidirectional buffers can have either a weak pull-up resistor, a weak pull-down resistor, or a weak "keeper" circuit. Control this feature by adding the appropriate primitive to the output net of the OBUFT (PULLUP, PULLDOWN, or KEEPER).

The weak "keeper" circuit requires the input buffer within the IOB to sample the I/O signal. So, OBUFTs programmed for an I/O standard that requires a  $V_{REF}$  have automatic placement of a  $V_{REF}$  in the bank with an OBUFT configured with a weak "keeper" circuit. This restriction does not affect most circuit design as applications using an OBUFT configured with a weak "keeper" typically implement a bidirectional I/O. In this case the IBUF (and the corresponding  $V_{REF}$ ) are explicitly placed.

The LOC property can specify a location for the OBUFT.

## IOBUF

Use the IOBUF primitive for bidirectional signals that require both an input buffer and a 3-state output buffer with an active high 3-state pin. The generic input/output buffer IOBUF appears in Figure 40.

With no extension or property specified for the generic IOBUF primitive, the assumed standard is LVTTL input buffer and slew rate limited LVTTL with 12 mA drive strength for the output buffer.

The LVTTL IOBUF can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL bidirectional buffers have selectable output drive strengths.

The format for LVTTL IOBUF primitive names is as follows:

IOBUF\_<slew\_rate>\_<drive\_strength>

<slew\_rate> can be either F (Fast), or S (Slow) and <drive\_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24).

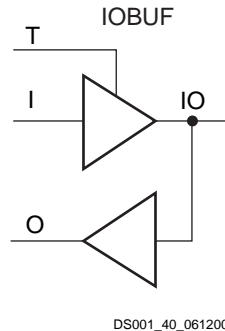


Figure 40: Input/Output Buffer Primitive (IOBUF)

When the IOBUF primitive supports an I/O standard such as LVTTTL, LVCMOS, or PCI33\_5, the IBUF automatically configures as a 5V tolerant input buffer unless the  $V_{CCO}$  for the bank is less than 2V. If the single-ended IBUF is placed in a bank with an HSTL standard ( $V_{CCO} < 2V$ ), the input buffer is not 5V tolerant.

The voltage reference signal is "banked" within the Spartan-II device on a half-edge basis such that for all packages there are eight independent  $V_{REF}$  banks internally. See Figure 36, page 39 for a representation of the Spartan-II FPGA I/O banks. Within each bank approximately one of every six I/O pins is automatically configured as a  $V_{REF}$  input.

Additional restrictions on the Versatile I/O IOBUF placement require that within a given  $V_{CCO}$  bank each IOBUF must share the same output source drive voltage. Input buffers of any type and output buffers that do not require  $V_{CCO}$  can be placed within the same  $V_{CCO}$  bank. The LOC property can specify a location for the IOBUF.

An optional delay element is associated with the input path in each IOBUF. When the IOBUF drives an input flip-flop within the IOB, the delay element activates by default to ensure a zero hold-time requirement. Override this default with the NODELAY=TRUE property.

In the case when the IOBUF does not drive an input flip-flop within the IOB, the delay element de-activates by default to provide higher performance. To delay the input signal, activate the delay element with the DELAY=TRUE property.

3-state output buffers and bidirectional buffers can have either a weak pull-up resistor, a weak pull-down resistor, or a weak "keeper" circuit. Control this feature by adding the appropriate primitive to the output net of the IOBUF (PULLUP, PULLDOWN, or KEEPER).

## Versatile I/O Properties

Access to some of the Versatile I/O features (for example, location constraints, input delay, output drive strength, and slew rate) is available through properties associated with these features.

### Input Delay Properties

An optional delay element is associated with each IBUF. When the IBUF drives a flip-flop within the IOB, the delay element activates by default to ensure a zero hold-time requirement. Use the NODELAY=TRUE property to override this default.

In the case when the IBUF does not drive a flip-flop within the IOB, the delay element by default de-activates to provide higher performance. To delay the input signal, activate the delay element with the DELAY=TRUE property.

### IOB Flip-Flop/Latch Property

The I/O Block (IOB) includes an optional register on the input path, an optional register on the output path, and an optional register on the 3-state control pin. The design implementation software automatically takes advantage of these registers when the following option for the Map program is specified:

```
map -pr b <filename>
```

Alternatively, the IOB = TRUE property can be placed on a register to force the mapper to place the register in an IOB.

### Location Constraints

Specify the location of each Versatile I/O primitive with the location constraint LOC attached to the Versatile I/O primitive. The external port identifier indicates the value of the location constrain. The format of the port identifier depends on the package chosen for the specific design.

The LOC properties use the following form:

```
LOC=A42
```

```
LOC=P37
```

### Output Slew Rate Property

In the case of the LVTTTL output buffers (OBUF, OBUFT, and IOBUF), slew rate control can be programmed with the SLEW= property. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals. The SLEW= property has one of the two following values.

```
SLEW=SLOW
```

```
SLEW=FAST
```

### Output Drive Strength Property

For the LVTTTL output buffers (OBUF, OBUFT, and IOBUF, the desired drive strength can be specified with the DRIVE=



## SSTL2\_I

A sample circuit illustrating a valid termination technique for SSTL2\_I appears in Figure 49. DC voltage specifications appear in Table 27 for the SSTL2\_I standard. See "DC Specifications" in Module 3 for the actual FPGA characteristics

**SSTL2 Class I**

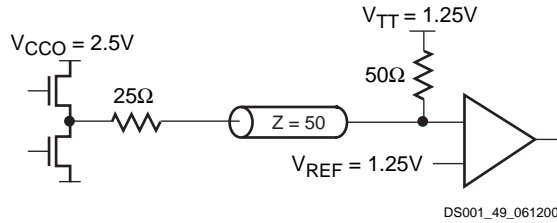


Figure 49: Terminated SSTL2 Class I

Table 27: SSTL2\_I Voltage Specifications

Parameter	Min	Typ	Max
$V_{CCO}$	2.3	2.5	2.7
$V_{REF} = 0.5 \times V_{CCO}$	1.15	1.25	1.35
$V_{TT} = V_{REF} + N^{(1)}$	1.11	1.25	1.39
$V_{IH} \geq V_{REF} + 0.18$	1.33	1.43	3.0 <sup>(2)</sup>
$V_{IL} \leq V_{REF} - 0.18$	-0.3 <sup>(3)</sup>	1.07	1.17
$V_{OH} \geq V_{REF} + 0.61$	1.76	-	-
$V_{OL} \leq V_{REF} - 0.61$	-	-	0.74
$I_{OH}$ at $V_{OH}$ (mA)	-7.6	-	-
$I_{OL}$ at $V_{OL}$ (mA)	7.6	-	-

**Notes:**

1. N must be greater than or equal to -0.04 and less than or equal to 0.04.
2.  $V_{IH}$  maximum is  $V_{CCO} + 0.3$ .
3.  $V_{IL}$  minimum does not conform to the formula.

## SSTL2 Class II

A sample circuit illustrating a valid termination technique for SSTL2\_II appears in Figure 50. DC voltage specifications appear in Table 28 for the SSTL2\_II standard. See "DC Specifications" in Module 3 for the actual FPGA characteristics.

**SSTL2 Class II**

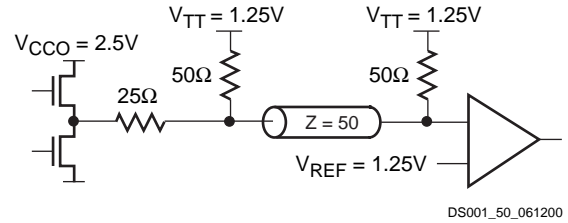


Figure 50: Terminated SSTL2 Class II

Table 28: SSTL2\_II Voltage Specifications

Parameter	Min	Typ	Max
$V_{CCO}$	2.3	2.5	2.7
$V_{REF} = 0.5 \times V_{CCO}$	1.15	1.25	1.35
$V_{TT} = V_{REF} + N^{(1)}$	1.11	1.25	1.39
$V_{IH} \geq V_{REF} + 0.18$	1.33	1.43	3.0 <sup>(2)</sup>
$V_{IL} \leq V_{REF} - 0.18$	-0.3 <sup>(3)</sup>	1.07	1.17
$V_{OH} \geq V_{REF} + 0.8$	1.95	-	-
$V_{OL} \leq V_{REF} - 0.8$	-	-	0.55
$I_{OH}$ at $V_{OH}$ (mA)	-15.2	-	-
$I_{OL}$ at $V_{OL}$ (mA)	15.2	-	-

**Notes:**

1. N must be greater than or equal to -0.04 and less than or equal to 0.04.
2.  $V_{IH}$  maximum is  $V_{CCO} + 0.3$ .
3.  $V_{IL}$  minimum does not conform to the formula.

Input/Output Standard	$V_{IL}$		$V_{IH}$		$V_{OL}$	$V_{OH}$	$I_{OL}$	$I_{OH}$
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
CTT	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.4$	$V_{REF} + 0.4$	8	-8
AGP	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	10% $V_{CCO}$	90% $V_{CCO}$	Note (2)	Note (2)

**Notes:**

1.  $V_{OL}$  and  $V_{OH}$  for lower drive currents are sample tested.
2. Tested according to the relevant specifications.

## Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-II devices unless otherwise noted.

### Global Clock Input to Output Delay for LVTTL, with DLL (Pin-to-Pin)<sup>(1)</sup>

Symbol	Description	Device	Speed Grade			Units
			All	-6	-5	
			Min	Max	Max	
$T_{ICKOFDLL}$	Global clock input to output delay using output flip-flop for LVTTL, 12 mA, fast slew rate, <i>with</i> DLL.	All		2.9	3.3	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see the tables ["Constants for Calculating TIOOP"](#) and ["Delay Measurement Methodology,"](#) page 60.
3. DLL output jitter is already included in the timing calculation.
4. For data *output* with different standards, adjust delays with the values shown in ["IOB Output Delay Adjustments for Different Standards,"](#) page 59. For a global clock input with standards other than LVTTL, adjust delays with values from the ["I/O Standard Global Clock Input Adjustments,"](#) page 61.

### Global Clock Input to Output Delay for LVTTL, without DLL (Pin-to-Pin)<sup>(1)</sup>

Symbol	Description	Device	Speed Grade			Units
			All	-6	-5	
			Min	Max	Max	
$T_{ICKOF}$	Global clock input to output delay using output flip-flop for LVTTL, 12 mA, fast slew rate, <i>without</i> DLL.	XC2S15		4.5	5.4	ns
		XC2S30		4.5	5.4	ns
		XC2S50		4.5	5.4	ns
		XC2S100		4.6	5.5	ns
		XC2S150		4.6	5.5	ns
		XC2S200		4.7	5.6	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see the tables ["Constants for Calculating TIOOP"](#) and ["Delay Measurement Methodology,"](#) page 60.
3. For data *output* with different standards, adjust delays with the values shown in ["IOB Output Delay Adjustments for Different Standards,"](#) page 59. For a global clock input with standards other than LVTTL, adjust delays with values from the ["I/O Standard Global Clock Input Adjustments,"](#) page 61.

## CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-6		-5		
		Min	Max	Min	Max	
Sequential Delays						
T <sub>SHCKO16</sub>	Clock CLK to X/Y outputs (WE active, 16 x 1 mode)	-	2.2	-	2.6	ns
T <sub>SHCKO32</sub>	Clock CLK to X/Y outputs (WE active, 32 x 1 mode)	-	2.5	-	3.0	ns
Setup/Hold Times with Respect to Clock CLK <sup>(1)</sup>						
T <sub>AS</sub> / T <sub>AH</sub>	F/G address inputs	0.7 / 0	-	0.7 / 0	-	ns
T <sub>DS</sub> / T <sub>DH</sub>	BX/BY data inputs (DIN)	0.8 / 0	-	0.9 / 0	-	ns
T <sub>WS</sub> / T <sub>WH</sub>	CE input (WS)	0.9 / 0	-	1.0 / 0	-	ns
Clock CLK						
T <sub>WPH</sub>	Minimum pulse width, High	-	2.9	-	2.9	ns
T <sub>WPL</sub>	Minimum pulse width, Low	-	2.9	-	2.9	ns
T <sub>WC</sub>	Minimum clock period to meet address write cycle time	-	5.8	-	5.8	ns

**Notes:**

1. A zero hold time listing indicates no hold time or a negative hold time.

## CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		-6		-5		
		Min	Max	Min	Max	
Sequential Delays						
T <sub>REG</sub>	Clock CLK to X/Y outputs	-	3.47	-	3.88	ns
Setup Times with Respect to Clock CLK						
T <sub>SHDICK</sub>	BX/BY data inputs (DIN)	0.8	-	0.9	-	ns
T <sub>SHCECK</sub>	CE input (WS)	0.9	-	1.0	-	ns
Clock CLK						
T <sub>SRPH</sub>	Minimum pulse width, High	-	2.9	-	2.9	ns
T <sub>SRPL</sub>	Minimum pulse width, Low	-	2.9	-	2.9	ns

## Introduction

This section describes how the various pins on a Spartan®-II FPGA connect within the supported component packages, and provides device-specific thermal characteristics. Spartan-II FPGAs are available in both standard and Pb-free, RoHS versions of each package, with the Pb-free version adding a “G” to the middle of the package code. Except for the thermal characteristics, all

information for the standard package applies equally to the Pb-free package.

## Pin Types

Most pins on a Spartan-II FPGA are general-purpose, user-defined I/O pins. There are, however, different functional types of pins on Spartan-II FPGA packages, as outlined in [Table 35](#).

**Table 35: Pin Definitions**

Pin Name	Dedicated	Direction	Description
GCK0, GCK1, GCK2, GCK3	No	Input	Clock input pins that connect to Global Clock Buffers. These pins become user inputs when not needed for clocks.
M0, M1, M2	Yes	Input	Mode pins are used to specify the configuration mode.
CCLK	Yes	Input or Output	The configuration Clock I/O pin. It is an input for slave-parallel and slave-serial modes, and output in master-serial mode.
PROGRAM	Yes	Input	Initiates a configuration sequence when asserted Low.
DONE	Yes	Bidirectional	Indicates that configuration loading is complete, and that the start-up sequence is in progress. The output may be open drain.
INIT	No	Bidirectional (Open-drain)	When Low, indicates that the configuration memory is being cleared. This pin becomes a user I/O after configuration.
BUSY/DOUT	No	Output	In Slave Parallel mode, BUSY controls the rate at which configuration data is loaded. This pin becomes a user I/O after configuration unless the Slave Parallel port is retained. In serial modes, DOUT provides configuration data to downstream devices in a daisy-chain. This pin becomes a user I/O after configuration.
D0/DIN, D1, D2, D3, D4, D5, D6, D7	No	Input or Output	In Slave Parallel mode, D0-D7 are configuration data input pins. During readback, D0-D7 are output pins. These pins become user I/Os after configuration unless the Slave Parallel port is retained. In serial modes, DIN is the single data input. This pin becomes a user I/O after configuration.
WRITE	No	Input	In Slave Parallel mode, the active-low Write Enable signal. This pin becomes a user I/O after configuration unless the Slave Parallel port is retained.
CS	No	Input	In Slave Parallel mode, the active-low Chip Select signal. This pin becomes a user I/O after configuration unless the Slave Parallel port is retained.
TDI, TDO, TMS, TCK	Yes	Mixed	Boundary Scan Test Access Port pins (IEEE 1149.1).
V <sub>CCINT</sub>	Yes	Input	Power supply pins for the internal core logic.
V <sub>CCO</sub>	Yes	Input	Power supply pins for output drivers (subject to banking rules)
V <sub>REF</sub>	No	Input	Input threshold voltage pins. Become user I/Os when an external threshold voltage is not needed (subject to banking rules).
GND	Yes	Input	Ground.
IRDY, TRDY	No	See PCI core documentation	These signals can only be accessed when using Xilinx® PCI cores. If the cores are not used, these pins are available as user I/Os.

## XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
V <sub>CCINT</sub>	-	P85	P24	A9	P171	-
I/O	1	-	P23	D8	P172	24
I/O	1	-	P22	C8	P173	27
I/O	1	-	-	-	P174	30
I/O	1	-	-	-	P175	33
I/O	1	-	-	-	P176	36
GND	-	-	-	-	P177	-
I/O, V <sub>REF</sub>	1	P86	P21	B8	P178	39
I/O	1	-	-	-	P179	42
I/O	1	-	P20	A8	P180	45
I/O	1	P87	P19	B7	P181	48
I, GCK2	1	P88	P18	A7	P182	54
GND	-	P89	P17	C7	P183	-
V <sub>CCO</sub>	1	P90	P16	D7	P184	-
V <sub>CCO</sub>	0	P90	P16	D7	P184	-
I, GCK3	0	P91	P15	A6	P185	55
V <sub>CCINT</sub>	-	P92	P14	B6	P186	-
I/O	0	-	P13	C6	P187	62
I/O	0	-	-	-	P188	65
I/O, V <sub>REF</sub>	0	P93	P12	D6	P189	68
GND	-	-	-	-	P190	-
I/O	0	-	-	-	P191	71
I/O	0	-	-	-	P192	74
I/O	0	-	-	-	P193	77
I/O	0	-	P11	A5	P194	80
I/O	0	-	P10	B5	P195	83
V <sub>CCINT</sub>	-	P94	P9	C5	P196	-
V <sub>CCO</sub>	0	-	-	-	P197	-
GND	-	-	P8	D5	P198	-
I/O	0	P95	P7	A4	P199	86
I/O	0	P96	P6	B4	P200	89
I/O	0	-	-	-	P201	92

## XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
I/O, V <sub>REF</sub>	0	P97	P5	C4	P203	95
I/O	0	-	-	-	P204	98
I/O	0	-	P4	A3	P205	101
I/O	0	P98	P3	B3	P206	104
TCK	-	P99	P2	C3	P207	-
V <sub>CCO</sub>	0	P100	P1	A2	P208	-
V <sub>CCO</sub>	7	P100	P144	B2	P208	-

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### Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. See "V<sub>CCO</sub> Banks" for details on V<sub>CCO</sub> banking.

## Additional XC2S30 Package Pins

### VQ100

Not Connected Pins					
P28	P29	-	-	-	-

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### TQ144

Not Connected Pins					
P104	P105	-	-	-	-

11/02/00

### CS144

Not Connected Pins					
M3	N3	-	-	-	-

11/02/00

### PQ208

Not Connected Pins					
P7	P13	P38	P44	P55	P56
P60	P97	P112	P118	P143	P149
P165	P202	-	-	-	-

11/02/00

### Notes:

1. For the PQ208 package, P13, P38, P118, and P143, which are Not Connected Pins on the XC2S30, are assigned to V<sub>CCINT</sub> on larger devices.



## XC2S50 Device Pinouts

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
GND	-	P143	P1	GND*	-
TMS	-	P142	P2	D3	-
I/O	7	P141	P3	C2	149
I/O	7	-	-	A2	152
I/O	7	P140	P4	B1	155
I/O	7	-	-	E3	158
I/O	7	-	P5	D2	161
GND	-	-	-	GND*	-
I/O, V <sub>REF</sub>	7	P139	P6	C1	164
I/O	7	-	P7	F3	167
I/O	7	-	-	E2	170
I/O	7	P138	P8	E4	173
I/O	7	P137	P9	D1	176
I/O	7	P136	P10	E1	179
GND	-	P135	P11	GND*	-
V <sub>CCO</sub>	7	-	P12	V <sub>CCO</sub> Bank 7*	-
V <sub>CCINT</sub>	-	-	P13	V <sub>CCINT</sub> *	-
I/O	7	P134	P14	F2	182
I/O	7	P133	P15	G3	185
I/O	7	-	-	F1	188
I/O	7	-	P16	F4	191
I/O	7	-	P17	F5	194
I/O	7	-	P18	G2	197
GND	-	-	P19	GND*	-
I/O, V <sub>REF</sub>	7	P132	P20	H3	200
I/O	7	P131	P21	G4	203
I/O	7	-	-	H2	206
I/O	7	P130	P22	G5	209
I/O	7	-	P23	H4	212
I/O, IRDY <sup>(1)</sup>	7	P129	P24	G1	215
GND	-	P128	P25	GND*	-
V <sub>CCO</sub>	7	P127	P26	V <sub>CCO</sub> Bank 7*	-
V <sub>CCO</sub>	6	P127	P26	V <sub>CCO</sub> Bank 6*	-
I/O, TRDY <sup>(1)</sup>	6	P126	P27	J2	218
V <sub>CCINT</sub>	-	P125	P28	V <sub>CCINT</sub> *	-
I/O	6	P124	P29	H1	224
I/O	6	-	-	J4	227
I/O	6	P123	P30	J1	230
I/O, V <sub>REF</sub>	6	P122	P31	J3	233

## XC2S50 Device Pinouts (Continued)

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
GND	-	-	P32	GND*	-
I/O	6	-	P33	K5	236
I/O	6	-	P34	K2	239
I/O	6	-	P35	K1	242
I/O	6	-	-	K3	245
I/O	6	P121	P36	L1	248
I/O	6	P120	P37	L2	251
V <sub>CCINT</sub>	-	-	P38	V <sub>CCINT</sub> *	-
V <sub>CCO</sub>	6	-	P39	V <sub>CCO</sub> Bank 6*	-
GND	-	P119	P40	GND*	-
I/O	6	P118	P41	K4	254
I/O	6	P117	P42	M1	257
I/O	6	P116	P43	L4	260
I/O	6	-	-	M2	263
I/O	6	-	P44	L3	266
I/O, V <sub>REF</sub>	6	P115	P45	N1	269
GND	-	-	-	GND*	-
I/O	6	-	P46	P1	272
I/O	6	-	-	L5	275
I/O	6	P114	P47	N2	278
I/O	6	-	-	M4	281
I/O	6	P113	P48	R1	284
I/O	6	P112	P49	M3	287
M1	-	P111	P50	P2	290
GND	-	P110	P51	GND*	-
M0	-	P109	P52	N3	291
V <sub>CCO</sub>	6	P108	P53	V <sub>CCO</sub> Bank 6*	-
V <sub>CCO</sub>	5	P107	P53	V <sub>CCO</sub> Bank 5*	-
M2	-	P106	P54	R3	292
I/O	5	-	-	N5	299
I/O	5	P103	P57	T2	302
I/O	5	-	-	P5	305
I/O	5	-	P58	T3	308
GND	-	-	-	GND*	-
I/O, V <sub>REF</sub>	5	P102	P59	T4	311
I/O	5	-	P60	M6	314
I/O	5	-	-	T5	317
I/O	5	P101	P61	N6	320
I/O	5	P100	P62	R5	323

## XC2S50 Device Pinouts (Continued)

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
I/O	0	-	-	D8	83
I/O	0	-	P188	A6	86
I/O, V <sub>REF</sub>	0	P12	P189	B7	89
GND	-	-	P190	GND*	-
I/O	0	-	P191	C8	92
I/O	0	-	P192	D7	95
I/O	0	-	P193	E7	98
I/O	0	P11	P194	C7	104
I/O	0	P10	P195	B6	107
V <sub>CCINT</sub>	-	P9	P196	V <sub>CCINT</sub> *	-
V <sub>CCO</sub>	0	-	P197	V <sub>CCO</sub> Bank 0*	-
GND	-	P8	P198	GND*	-
I/O	0	P7	P199	A5	110
I/O	0	P6	P200	C6	113
I/O	0	-	P201	B5	116
I/O	0	-	-	D6	119
I/O	0	-	P202	A4	122
I/O, V <sub>REF</sub>	0	P5	P203	B4	125
GND	-	-	-	GND*	-
I/O	0	-	P204	E6	128
I/O	0	-	-	D5	131
I/O	0	P4	P205	A3	134
I/O	0	-	-	C5	137
I/O	0	P3	P206	B3	140
TCK	-	P2	P207	C4	-
V <sub>CCO</sub>	0	P1	P208	V <sub>CCO</sub> Bank 0*	-
V <sub>CCO</sub>	7	P144	P208	V <sub>CCO</sub> Bank 7*	-

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### Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. Pads labelled GND\*, V<sub>CCINT</sub>\*, V<sub>CCO</sub> Bank 0\*, V<sub>CCO</sub> Bank 1\*, V<sub>CCO</sub> Bank 2\*, V<sub>CCO</sub> Bank 3\*, V<sub>CCO</sub> Bank 4\*, V<sub>CCO</sub> Bank 5\*, V<sub>CCO</sub> Bank 6\*, V<sub>CCO</sub> Bank 7\* are internally bonded to independent ground or power planes within the package.
3. See "VCCO Banks" for details on V<sub>CCO</sub> banking.

## Additional XC2S50 Package Pins

### TQ144

Not Connected Pins					
P104	P105	-	-	-	-

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## XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name						
Function	Bank	TQ144	PQ208	FG256	FG456	Bndry Scan
I/O	0	-	P188	A6	C10	107
I/O, V <sub>REF</sub>	0	P12	P189	B7	A9	110
GND	-	-	P190	GND*	GND*	-
I/O	0	-	P191	C8	B9	113
I/O	0	-	P192	D7	E10	116
I/O	0	-	P193	E7	A8	122
I/O	0	-	-	-	D9	125
I/O	0	P11	P194	C7	E9	128
I/O	0	P10	P195	B6	A7	131
V <sub>CCINT</sub>	-	P9	P196	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
V <sub>CCO</sub>	0	-	P197	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
GND	-	P8	P198	GND*	GND*	-
I/O	0	P7	P199	A5	B7	134
I/O, V <sub>REF</sub>	0	P6	P200	C6	E8	137
I/O	0	-	-	-	D8	140
I/O	0	-	P201	B5	C7	143
I/O	0	-	-	D6	D7	146
I/O	0	-	P202	A4	D6	152
I/O, V <sub>REF</sub>	0	P5	P203	B4	C6	155
V <sub>CCO</sub>	0	-	-	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
GND	-	-	-	GND*	GND*	-
I/O	0	-	P204	E6	B5	158
I/O	0	-	-	D5	E7	161
I/O	0	-	-	-	E6	164
I/O	0	P4	P205	A3	B4	167
I/O	0	-	-	C5	A3	170
I/O	0	P3	P206	B3	C5	176
TCK	-	P2	P207	C4	C4	-
V <sub>CCO</sub>	0	P1	P208	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
V <sub>CCO</sub>	7	P144	P208	V <sub>CCO</sub> Bank 7*	V <sub>CCO</sub> Bank 7*	-

04/18/01

### Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. Pads labelled GND\*, V<sub>CCINT</sub>\*, V<sub>CCO</sub> Bank 0\*, V<sub>CCO</sub> Bank 1\*, V<sub>CCO</sub> Bank 2\*, V<sub>CCO</sub> Bank 3\*, V<sub>CCO</sub> Bank 4\*, V<sub>CCO</sub> Bank 5\*, V<sub>CCO</sub> Bank 6\*, V<sub>CCO</sub> Bank 7\* are internally bonded to independent ground or power planes within the package.
3. See "VCCO Banks" for details on V<sub>CCO</sub> banking.

## Additional XC2S100 Package Pins

### TQ144

Not Connected Pins					
P104	P105	-	-	-	-

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### PQ208

Not Connected Pins					
P55	P56	-	-	-	-

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### FG256

V <sub>CCINT</sub> Pins					
C3	C14	D4	D13	E5	E12
M5	M12	N4	N13	P3	P14
V <sub>CCO</sub> Bank 0 Pins					
E8	F8	-	-	-	-
V <sub>CCO</sub> Bank 1 Pins					
E9	F9	-	-	-	-
V <sub>CCO</sub> Bank 2 Pins					
H11	H12	-	-	-	-
V <sub>CCO</sub> Bank 3 Pins					
J11	J12	-	-	-	-
V <sub>CCO</sub> Bank 4 Pins					
L9	M9	-	-	-	-
V <sub>CCO</sub> Bank 5 Pins					
L8	M8	-	-	-	-
V <sub>CCO</sub> Bank 6 Pins					
J5	J6	-	-	-	-
V <sub>CCO</sub> Bank 7 Pins					
H5	H6	-	-	-	-
GND Pins					
A1	A16	B2	B15	F6	F7
F10	F11	G6	G7	G8	G9
G10	G11	H7	H8	H9	H10
J7	J8	J9	J10	K6	K7
K8	K9	K10	K11	L6	L7
L10	L11	R2	R15	T1	T16
Not Connected Pins					
P4	R4	-	-	-	-

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### FG456

V <sub>CCINT</sub> Pins					
E5	E18	F6	F17	G7	G8
G9	G14	G15	G16	H7	H16
J7	J16	P7	P16	R7	R16
T7	T8	T9	T14	T15	T16
U6	U17	V5	V18	-	-
V <sub>CCO</sub> Bank 0 Pins					

## Additional XC2S100 Package Pins (Continued)

F10	F7	F8	F9	G10	G11
V <sub>CCO</sub> Bank 1 Pins					
F13	F14	F15	F16	G12	G13
V <sub>CCO</sub> Bank 2 Pins					
G17	H17	J17	K16	K17	L16
V <sub>CCO</sub> Bank 3 Pins					
M16	N16	N17	P17	R17	T17
V <sub>CCO</sub> Bank 4 Pins					
T12	T13	U13	U14	U15	U16
V <sub>CCO</sub> Bank 5 Pins					
T10	T11	U10	U7	U8	U9
V <sub>CCO</sub> Bank 6 Pins					
M7	N6	N7	P6	R6	T6
V <sub>CCO</sub> Bank 7 Pins					
G6	H6	J6	K6	K7	L7
GND Pins					
A1	A22	B2	B21	C3	C20
J9	J10	J11	J12	J13	J14
K9	K10	K11	K12	K13	K14
L9	L10	L11	L12	L13	L14
M9	M10	M11	M12	M13	M14
N9	N10	N11	N12	N13	N14
P9	P10	P11	P12	P13	P14
Y3	Y20	AA2	AA21	AB1	AB22
Not Connected Pins					
A2	A4	A5	A6	A12	A13
A14	A15	A17	B3	B6	B8
B11	B14	B16	B19	C1	C2
C8	C9	C12	C18	C22	D1
D4	D5	D10	D18	D19	D21
E4	E11	E13	E15	E16	E17
E19	E22	F4	F11	F22	G2
G3	G4	G19	G22	H1	H21
J1	J3	J4	J19	J20	K2
K18	K19	L2	L5	L18	L19
M2	M6	M17	M18	M21	N1
N5	N19	P1	P5	P19	P22
R1	R3	R20	R22	T5	T19
U3	U11	U18	V1	V2	V10
V12	V17	V3	V4	V6	V8
V20	V21	V22	W4	W5	W9
W13	W14	W15	W16	W19	Y5
Y14	Y18	Y22	AA1	AA3	AA6
AA9	AA10	AA11	AA16	AA17	AA18
AA22	AB3	AB4	AB7	AB8	AB12
AB14	AB21	-	-	-	-

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## XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	1	P174	B10	C14	72
I/O	1	-	-	B14	75
I/O	1	P175	D10	D13	81
I/O	1	P176	A10	C13	84
GND	-	P177	GND*	GND*	-
V <sub>CCO</sub>	1	-	V <sub>CCO</sub> Bank 1*	V <sub>CCO</sub> Bank 1*	-
I/O, V <sub>REF</sub>	1	P178	B9	B13	87
I/O	1	P179	E10	E12	90
I/O	1	-	A9	B12	93
I/O	1	P180	D9	D12	96
I/O	1	-	-	C12	99
I/O	1	P181	A8	D11	102
I, GCK2	1	P182	C9	A11	108
GND	-	P183	GND*	GND*	-
V <sub>CCO</sub>	1	P184	V <sub>CCO</sub> Bank 1*	V <sub>CCO</sub> Bank 1*	-
V <sub>CCO</sub>	0	P184	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
I, GCK3	0	P185	B8	C11	109
V <sub>CCINT</sub>	-	P186	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O	0	-	-	E11	116
I/O	0	P187	A7	A10	119
I/O	0	-	D8	B10	122
I/O	0	P188	A6	C10	125
I/O, V <sub>REF</sub>	0	P189	B7	A9	128
V <sub>CCO</sub>	0	-	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
GND	-	P190	GND*	GND*	-
I/O	0	P191	C8	B9	131
I/O	0	P192	D7	E10	134
I/O	0	-	-	D10	140
I/O	0	P193	E7	A8	143
I/O	0	-	-	D9	146
I/O	0	-	-	B8	149
I/O	0	P194	C7	E9	155
I/O	0	P195	B6	A7	158

## XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
V <sub>CCINT</sub>	-	P196	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
V <sub>CCO</sub>	0	P197	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
GND	-	P198	GND*	GND*	-
I/O	0	P199	A5	B7	161
I/O, V <sub>REF</sub>	0	P200	C6	E8	164
I/O	0	-	-	D8	167
I/O	0	P201	B5	C7	170
I/O	0	-	D6	D7	173
I/O	0	-	-	B6	176
I/O	0	-	-	A5	179
I/O	0	P202	A4	D6	182
I/O, V <sub>REF</sub>	0	P203	B4	C6	185
V <sub>CCO</sub>	0	-	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
GND	-	-	GND*	GND*	-
I/O	0	P204	E6	B5	188
I/O	0	-	D5	E7	191
I/O	0	-	-	A4	194
I/O	0	-	-	E6	197
I/O	0	P205	A3	B4	200
GND	-	-	GND*	GND*	-
I/O	0	-	C5	A3	203
I/O	0	-	-	B3	206
I/O	0	-	-	D5	209
I/O	0	P206	B3	C5	212
TCK	-	P207	C4	C4	-
V <sub>CCO</sub>	0	P208	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
V <sub>CCO</sub>	7	P208	V <sub>CCO</sub> Bank 7*	V <sub>CCO</sub> Bank 7*	-

04/18/01

### Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. Pads labelled GND\*, V<sub>CCINT</sub>\*, V<sub>CCO</sub> Bank 0\*, V<sub>CCO</sub> Bank 1\*, V<sub>CCO</sub> Bank 2\*, V<sub>CCO</sub> Bank 3\*, V<sub>CCO</sub> Bank 4\*, V<sub>CCO</sub> Bank 5\*, V<sub>CCO</sub> Bank 6\*, V<sub>CCO</sub> Bank 7\* are internally bonded to independent ground or power planes within the package.
3. See "VCCO Banks" for details on V<sub>CCO</sub> banking.



## XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	6	-	-	T2	449
I/O	6	P43	L4	U1	452
GND	-	-	GND*	GND*	-
I/O	6	-	M2	R5	455
I/O	6	-	-	V1	458
I/O	6	-	-	T5	461
I/O	6	P44	L3	U2	464
I/O, V <sub>REF</sub>	6	P45	N1	T3	467
V <sub>CCO</sub>	6	-	V <sub>CCO</sub> Bank 6*	V <sub>CCO</sub> Bank 6*	-
GND	-	-	GND*	GND*	-
I/O	6	P46	P1	T4	470
I/O	6	-	L5	W1	473
GND	-	-	GND*	GND*	-
I/O	6	-	-	V2	476
I/O	6	-	-	U4	482
I/O, V <sub>REF</sub>	6	P47	N2	Y1	485
GND	-	-	GND*	GND*	-
I/O	6	-	M4	W2	488
I/O	6	-	-	V3	491
I/O	6	-	-	V4	494
I/O	6	P48	R1	Y2	500
I/O	6	P49	M3	W3	503
M1	-	P50	P2	U5	506
GND	-	P51	GND*	GND*	-
M0	-	P52	N3	AB2	507
V <sub>CCO</sub>	6	P53	V <sub>CCO</sub> Bank 6*	V <sub>CCO</sub> Bank 6*	-
V <sub>CCO</sub>	5	P53	V <sub>CCO</sub> Bank 5*	V <sub>CCO</sub> Bank 5*	-
M2	-	P54	R3	Y4	508
I/O	5	-	-	W5	518
I/O	5	-	-	AB3	521
I/O	5	-	N5	V7	524
GND	-	-	GND*	GND*	-
I/O, V <sub>REF</sub>	5	P57	T2	Y6	527
I/O	5	-	-	AA4	530
I/O	5	-	-	AB4	536
I/O	5	-	P5	W6	539
I/O	5	P58	T3	Y7	542
GND	-	-	GND*	GND*	-

## XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
V <sub>CCO</sub>	5	-	V <sub>CCO</sub> Bank 5*	V <sub>CCO</sub> Bank 5*	-
I/O, V <sub>REF</sub>	5	P59	T4	AA5	545
I/O	5	P60	M6	AB5	548
I/O	5	-	-	V8	551
I/O	5	-	-	AA6	554
I/O	5	-	T5	AB6	557
GND	-	-	GND*	GND*	-
I/O	5	P61	N6	AA7	560
I/O	5	-	-	W7	563
I/O, V <sub>REF</sub>	5	P62	R5	W8	569
I/O	5	P63	P6	Y8	572
GND	-	P64	GND*	GND*	-
V <sub>CCO</sub>	5	P65	V <sub>CCO</sub> Bank 5*	V <sub>CCO</sub> Bank 5*	-
V <sub>CCINT</sub>	-	P66	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O	5	P67	R6	AA8	575
I/O	5	P68	M7	V9	578
I/O	5	-	-	AB8	581
I/O	5	-	-	W9	584
I/O	5	-	-	AB9	587
GND	-	-	GND*	GND*	-
I/O	5	P69	N7	Y9	590
I/O	5	-	-	V10	593
I/O	5	-	-	AA9	596
I/O	5	P70	T6	W10	599
I/O	5	P71	P7	AB10	602
GND	-	P72	GND*	GND*	-
V <sub>CCO</sub>	5	-	V <sub>CCO</sub> Bank 5*	V <sub>CCO</sub> Bank 5*	-
I/O, V <sub>REF</sub>	5	P73	P8	Y10	605
I/O	5	P74	R7	V11	608
I/O	5	-	-	AA10	614
I/O	5	-	T7	W11	617
I/O	5	P75	T8	AB11	620
I/O	5	-	-	U11	623
V <sub>CCINT</sub>	-	P76	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I, GCK1	5	P77	R8	Y11	635
V <sub>CCO</sub>	5	P78	V <sub>CCO</sub> Bank 5*	V <sub>CCO</sub> Bank 5*	-
V <sub>CCO</sub>	4	P78	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
GND	-	P79	GND*	GND*	-

## XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
V <sub>CCO</sub>	3	P117	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
V <sub>CCINT</sub>	-	P118	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O (D5)	3	P119	M16	R21	833
I/O	3	P120	K14	P18	836
I/O	3	-	-	R22	839
I/O	3	-	-	P19	842
I/O	3	-	L16	P20	845
GND	-	-	GND*	GND*	-
I/O	3	P121	K13	P21	848
I/O	3	-	-	N19	851
I/O	3	-	-	P22	854
I/O	3	P122	L15	N18	857
I/O	3	P123	K12	N20	860
GND	-	P124	GND*	GND*	-
V <sub>CCO</sub>	3	-	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
I/O, V <sub>REF</sub>	3	P125	K16	N21	863
I/O (D4)	3	P126	J16	N22	866
I/O	3	-	-	M17	872
I/O	3	-	J14	M19	875
I/O	3	P127	K15	M20	878
I/O	3	-	-	M18	881
V <sub>CCINT</sub>	-	P128	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O, TRDY <sup>(1)</sup>	3	P129	J15	M22	890
V <sub>CCO</sub>	3	P130	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
V <sub>CCO</sub>	2	P130	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
GND	-	P131	GND*	GND*	-
I/O, IRDY <sup>(1)</sup>	2	P132	H16	L20	893
I/O	2	P133	H14	L17	896
I/O	2	-	-	L18	902
I/O	2	P134	H15	L21	905
I/O	2	-	J13	L22	908
I/O	2	-	-	K19	911
I/O (D3)	2	P135	G16	K20	917
I/O, V <sub>REF</sub>	2	P136	H13	K21	920
V <sub>CCO</sub>	2	-	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
GND	-	P137	GND*	GND*	-
I/O	2	P138	G14	K22	923
I/O	2	P139	G15	J21	926

## XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	2	-	-	K18	929
I/O	2	-	-	J20	932
I/O	2	P140	G12	J18	935
GND	-	-	GND*	GND*	-
I/O	2	-	F16	J22	938
I/O	2	-	-	J19	941
I/O	2	-	-	H21	944
I/O	2	P141	G13	H19	947
I/O (D2)	2	P142	F15	H20	950
V <sub>CCINT</sub>	-	P143	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
V <sub>CCO</sub>	2	P144	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
GND	-	P145	GND*	GND*	-
I/O (D1)	2	P146	E16	H22	953
I/O, V <sub>REF</sub>	2	P147	F14	H18	956
I/O	2	-	-	G21	962
I/O	2	P148	D16	G18	965
GND	-	-	GND*	GND*	-
I/O	2	-	F12	G20	968
I/O	2	-	-	G19	971
I/O	2	-	-	F22	974
I/O	2	P149	E15	F19	977
I/O, V <sub>REF</sub>	2	P150	F13	F21	980
V <sub>CCO</sub>	2	-	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
GND	-	-	GND*	GND*	-
I/O	2	P151	E14	F20	983
I/O	2	-	C16	F18	986
GND	-	-	GND*	GND*	-
I/O	2	-	-	E22	989
I/O	2	-	-	E21	995
I/O, V <sub>REF</sub>	2	P152	E13	D22	998
GND	-	-	GND*	GND*	-
I/O	2	-	B16	E20	1001
I/O	2	-	-	D21	1004
I/O	2	-	-	C22	1007
I/O (DIN, D0)	2	P153	D14	D20	1013
I/O (DOUT, BUSY)	2	P154	C15	C21	1016
CCLK	2	P155	D15	B22	1019
V <sub>CCO</sub>	2	P156	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-

## XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
GND	-	P198	GND*	GND*	-
I/O	0	P199	A5	B7	188
I/O, V <sub>REF</sub>	0	P200	C6	E8	191
I/O	0	-	-	D8	197
I/O	0	P201	B5	C7	200
GND	-	-	GND*	GND*	-
I/O	0	-	D6	D7	203
I/O	0	-	-	B6	206
I/O	0	-	-	A5	209
I/O	0	P202	A4	D6	212
I/O, V <sub>REF</sub>	0	P203	B4	C6	215
V <sub>CCO</sub>	0	-	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
GND	-	-	GND*	GND*	-
I/O	0	P204	E6	B5	218
I/O	0	-	D5	E7	221
I/O	0	-	-	A4	224
I/O	0	-	-	E6	230
I/O, V <sub>REF</sub>	0	P205	A3	B4	233
GND	-	-	GND*	GND*	-
I/O	0	-	C5	A3	236
I/O	0	-	-	B3	239
I/O	0	-	-	D5	242
I/O	0	P206	B3	C5	248
TCK	-	P207	C4	C4	-
V <sub>CCO</sub>	0	P208	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
V <sub>CCO</sub>	7	P208	V <sub>CCO</sub> Bank 7*	V <sub>CCO</sub> Bank 7*	-

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### Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. Pads labelled GND\*, V<sub>CCINT</sub>\*, V<sub>CCO</sub> Bank 0\*, V<sub>CCO</sub> Bank 1\*, V<sub>CCO</sub> Bank 2\*, V<sub>CCO</sub> Bank 3\*, V<sub>CCO</sub> Bank 4\*, V<sub>CCO</sub> Bank 5\*, V<sub>CCO</sub> Bank 6\*, V<sub>CCO</sub> Bank 7\* are internally bonded to independent ground or power planes within the package.
3. See "VCCO Banks" for details on V<sub>CCO</sub> banking.

## Additional XC2S200 Package Pins

### PQ208

Not Connected Pins					
P55	P56	-	-	-	-

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### FG256

V <sub>CCINT</sub> Pins					
C3	C14	D4	D13	E5	E12
M5	M12	N4	N13	P3	P14
V <sub>CCO</sub> Bank 0 Pins					
E8	F8	-	-	-	-
V <sub>CCO</sub> Bank 1 Pins					
E9	F9	-	-	-	-
V <sub>CCO</sub> Bank 2 Pins					
H11	H12	-	-	-	-
V <sub>CCO</sub> Bank 3 Pins					
J11	J12	-	-	-	-
V <sub>CCO</sub> Bank 4 Pins					
L9	M9	-	-	-	-
V <sub>CCO</sub> Bank 5 Pins					
L8	M8	-	-	-	-
V <sub>CCO</sub> Bank 6 Pins					
J5	J6	-	-	-	-
V <sub>CCO</sub> Bank 7 Pins					
H5	H6	-	-	-	-
GND Pins					
A1	A16	B2	B15	F6	F7
F10	F11	G6	G7	G8	G9
G10	G11	H7	H8	H9	H10
J7	J8	J9	J10	K6	K7
K8	K9	K10	K11	L6	L7
L10	L11	R2	R15	T1	T16
Not Connected Pins					
P4	R4	-	-	-	-